

FE-SEM foil thickness measurements

Process

- Mount sister foils to Si wafers
 - Static for thinner foils
 - “glue” with aerodag carbon suspension for thicker
- Mamun makes images
- Use ImageJ software to measure .tiff images saved from FE-SEM process

Comparison of edge find tool

- Analyzed images 05 and 06 with edge contrast on or off
- Find that the edge contrast tends to skew measurements slightly larger
 - Variation between images larger than variation between images
- Conclusion:
 - make sure to go on inside edges of “edge find” line to get more accurate results

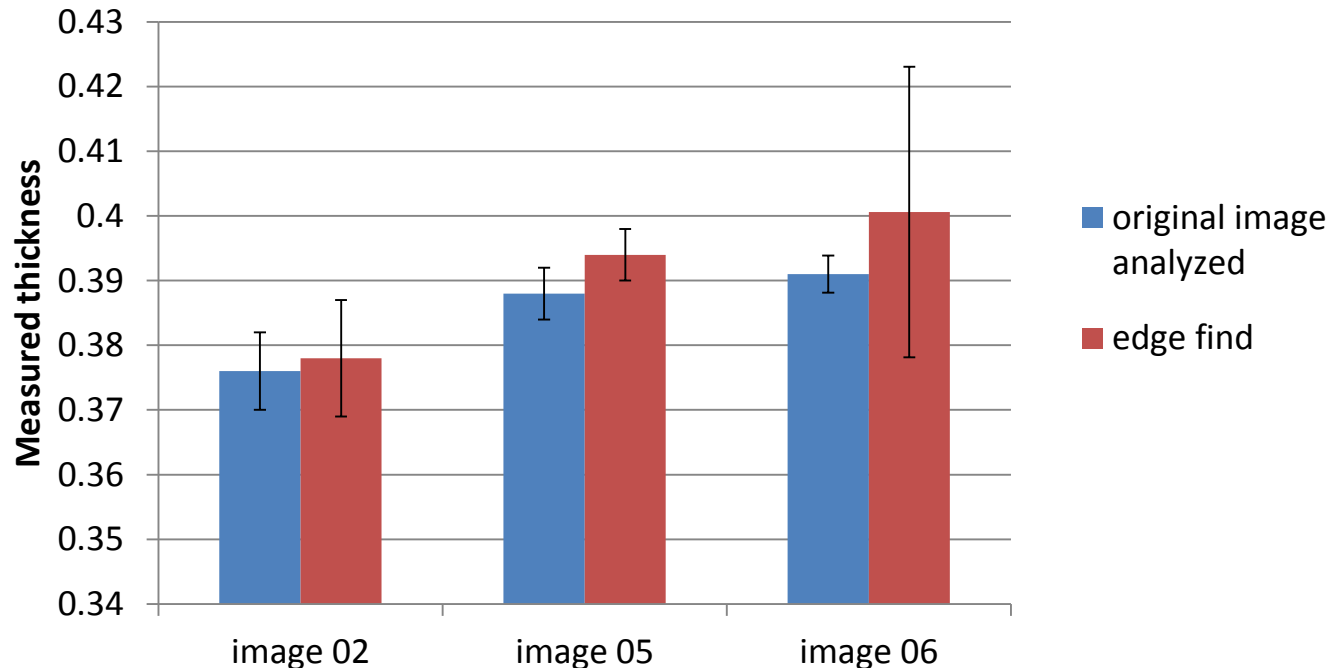
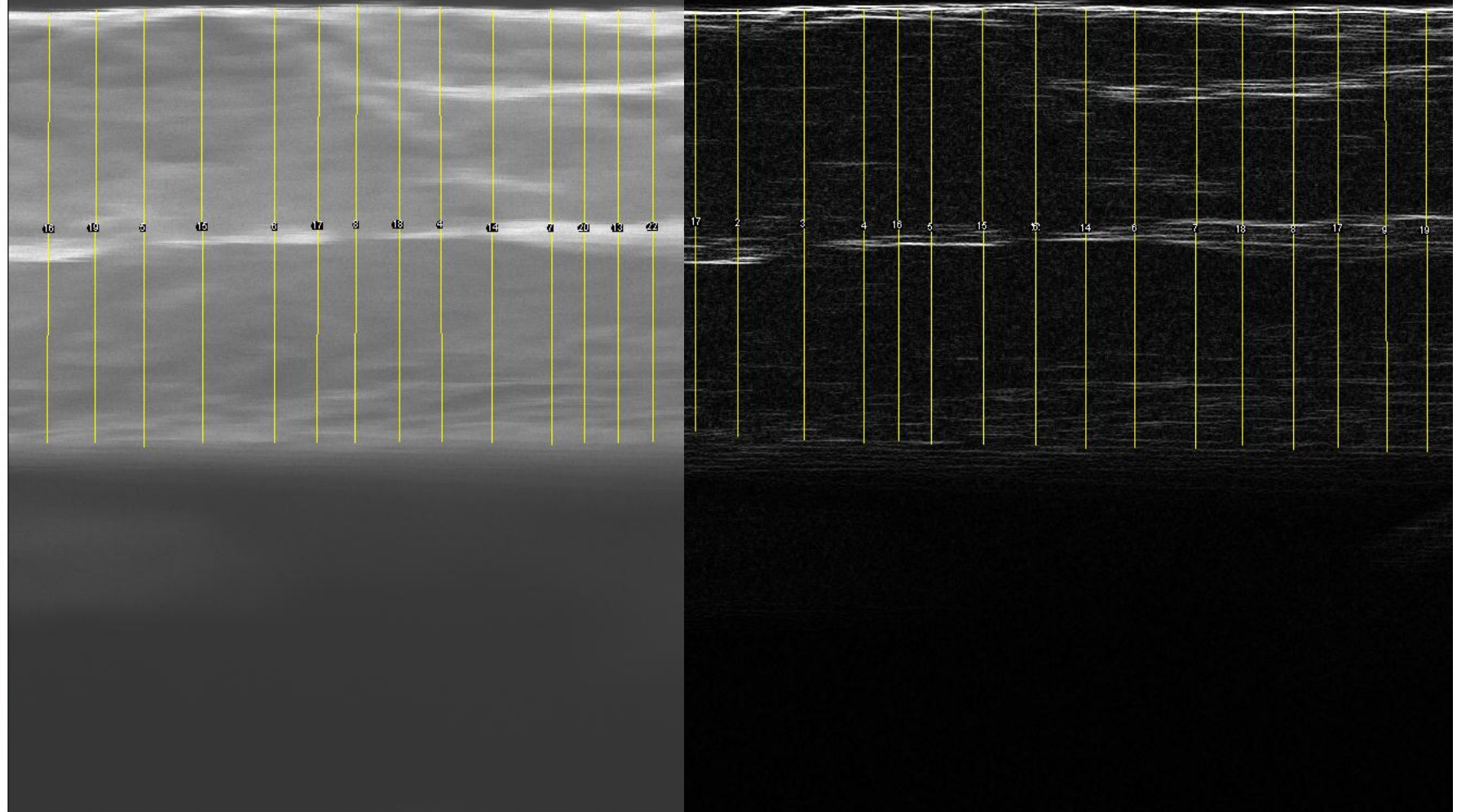
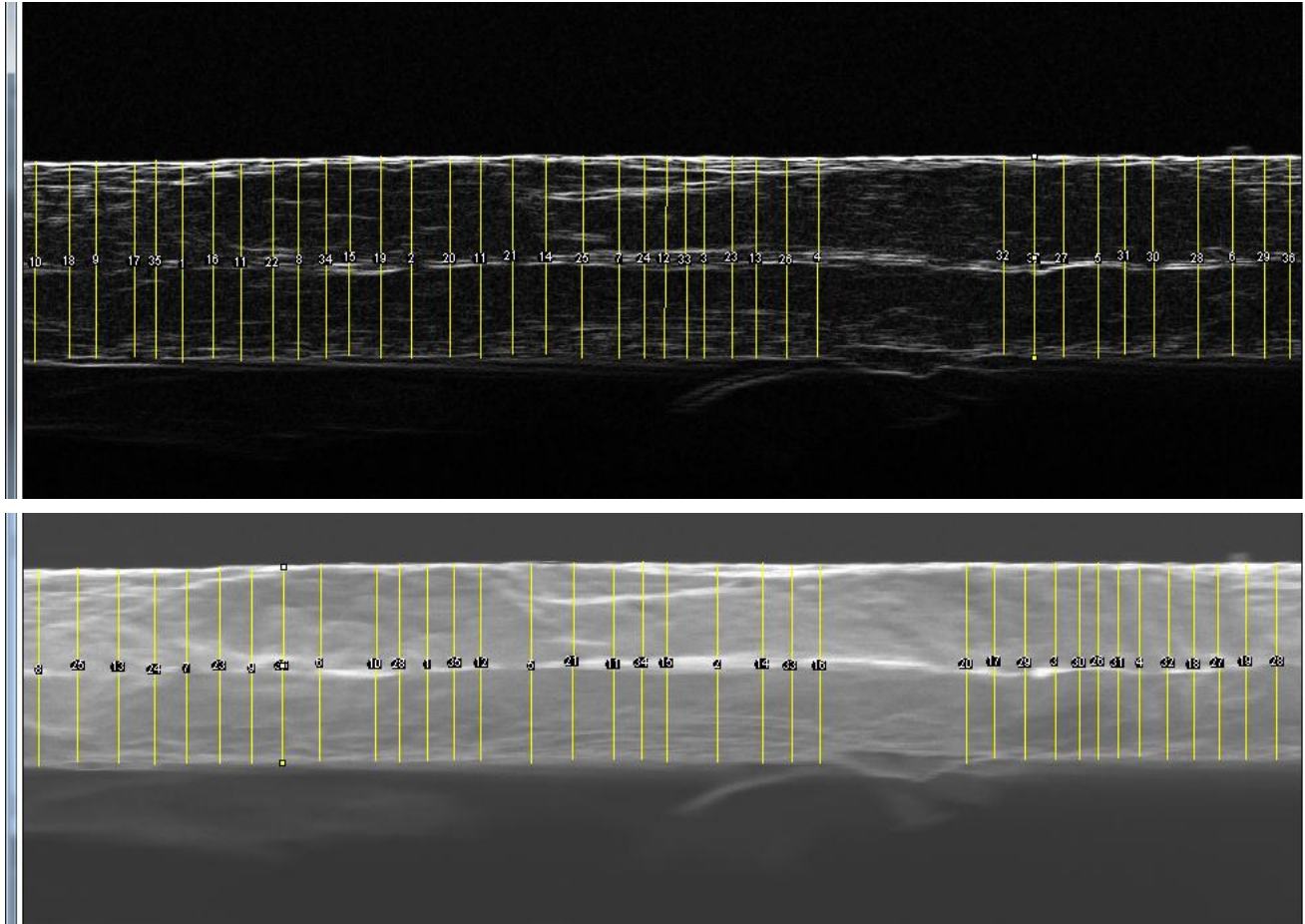


Image 06 Measurement with and without edge find

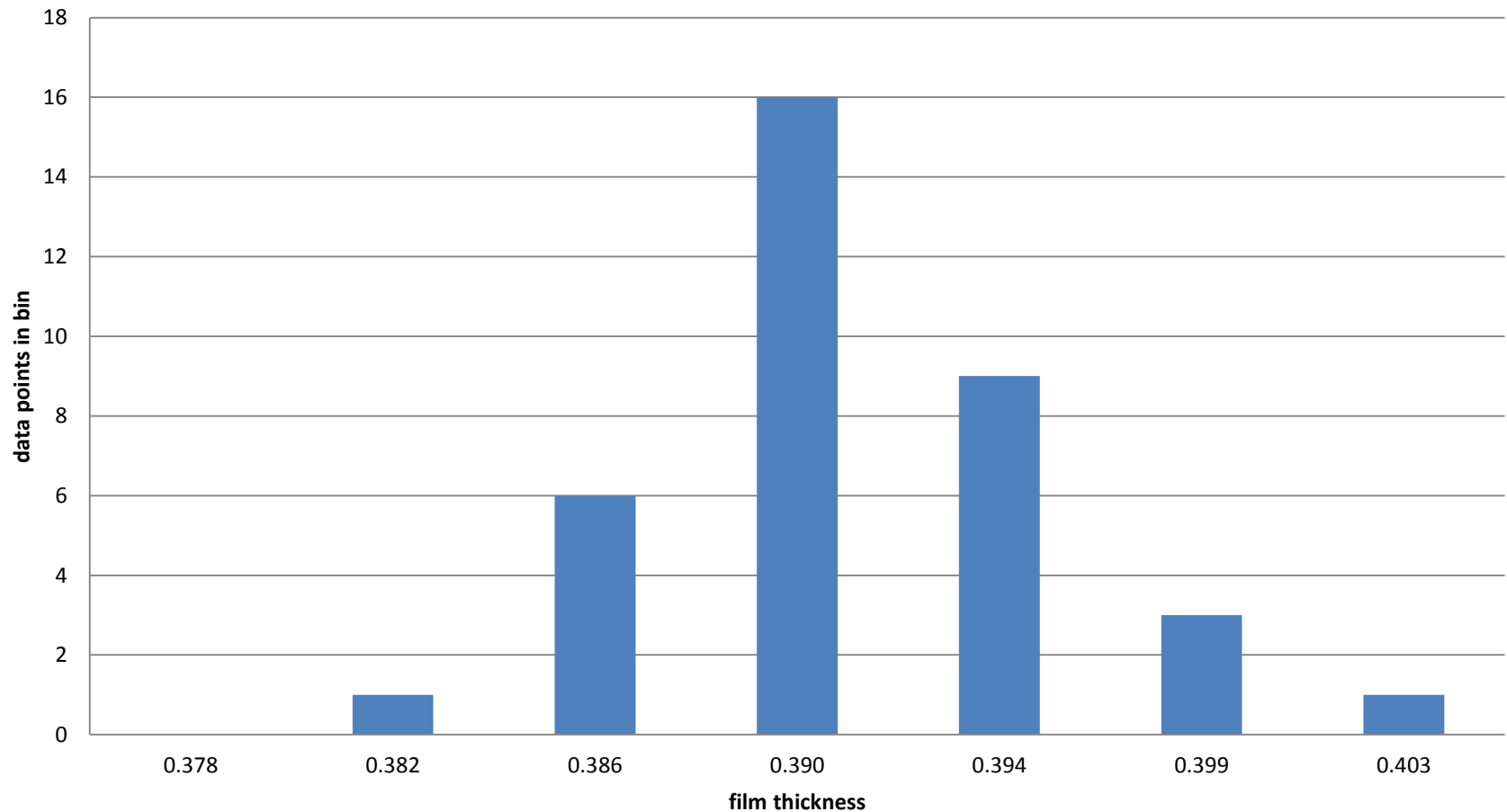


S4700 15.0kV 11.4mm x100k SE(U) S4700 15.0kV 11.4mm x100k SE(U)

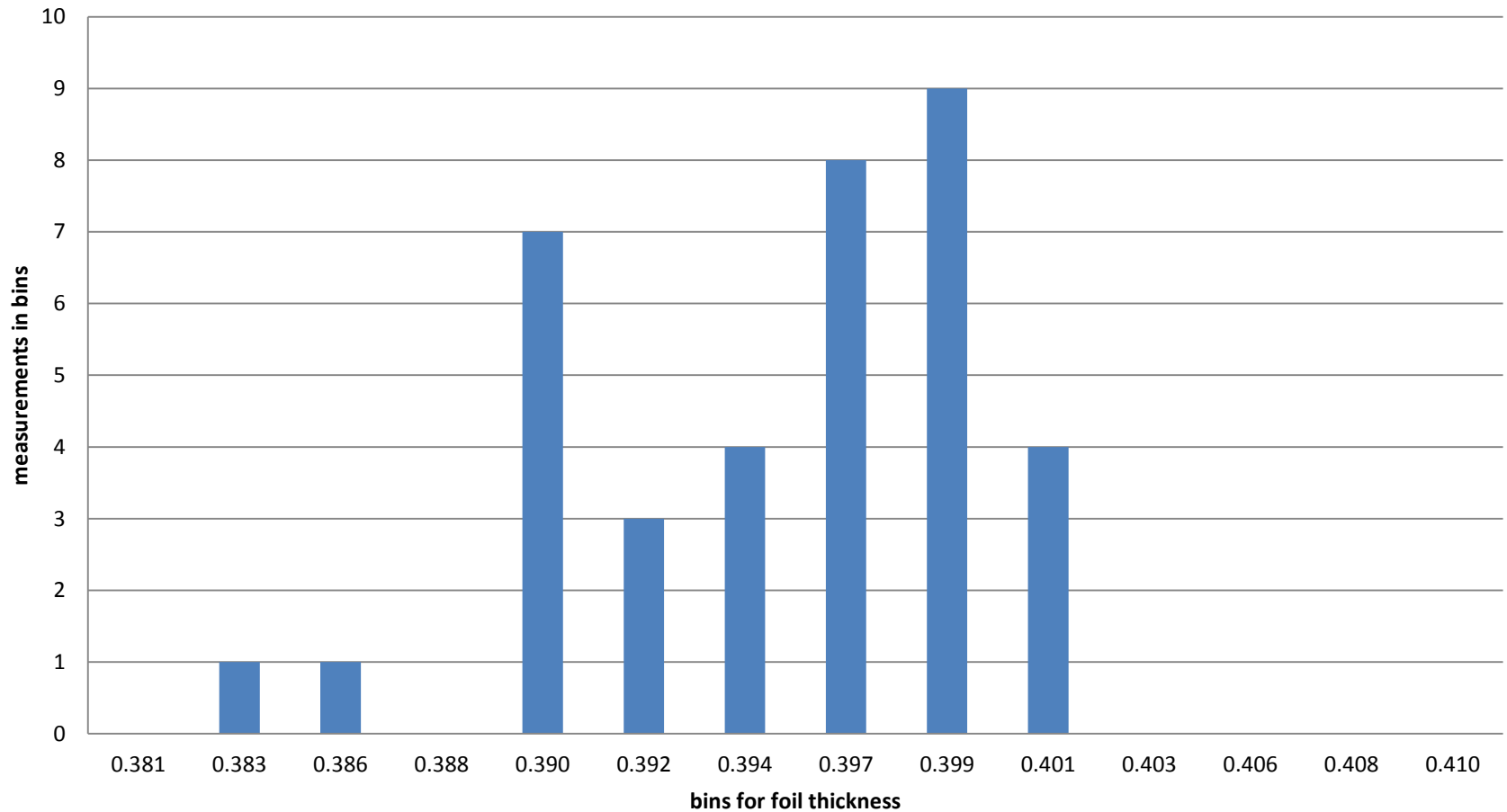
Image 05: original image, edge find



Statistical analysis of points measured spots selected by eye, original image



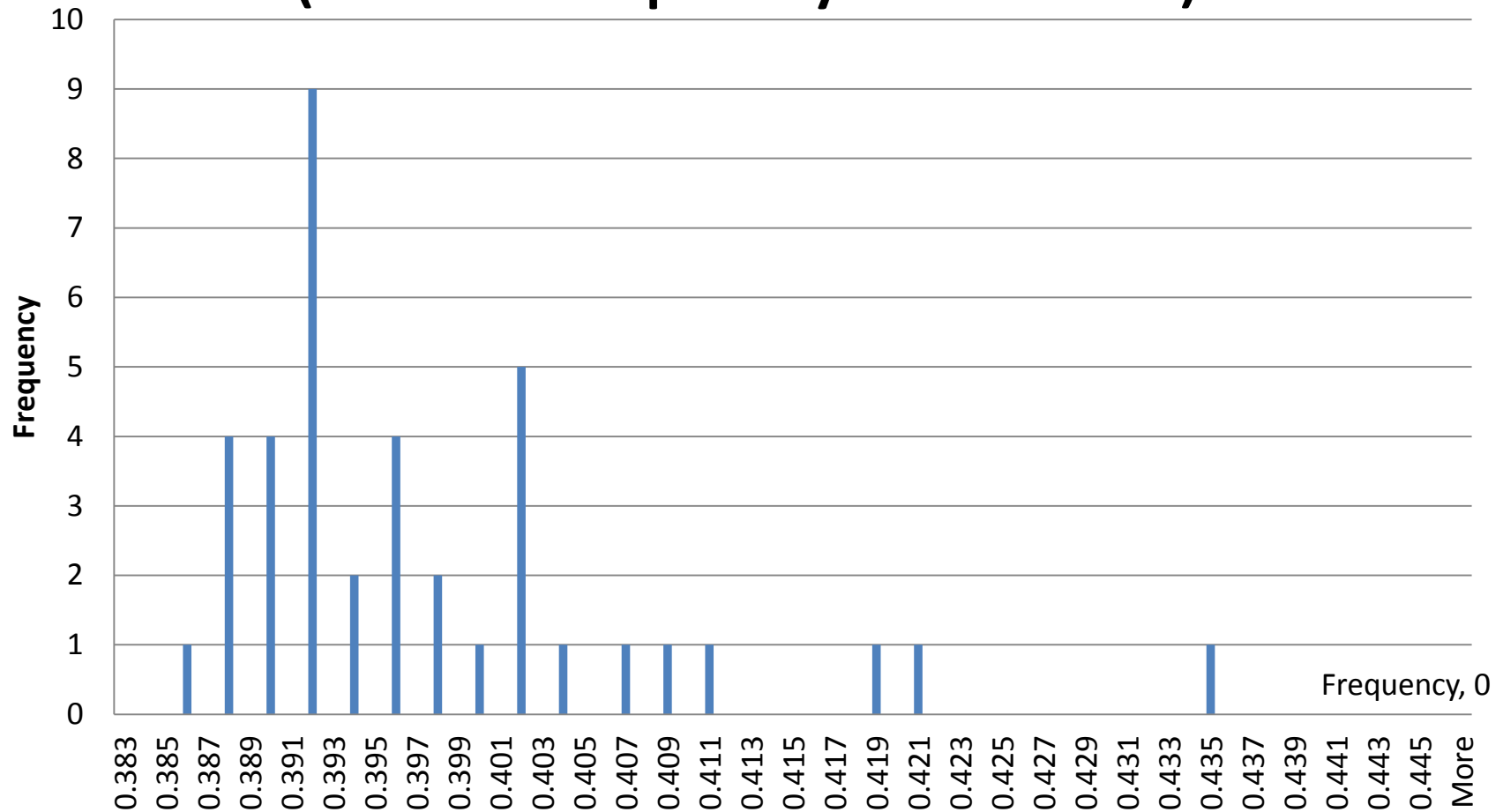
Thickness distribution, edge find 5613D image05, spots selected by eye



Statistics from even distribution 5613

M05 even stripe distance

(don't skip any oddities)



5613D

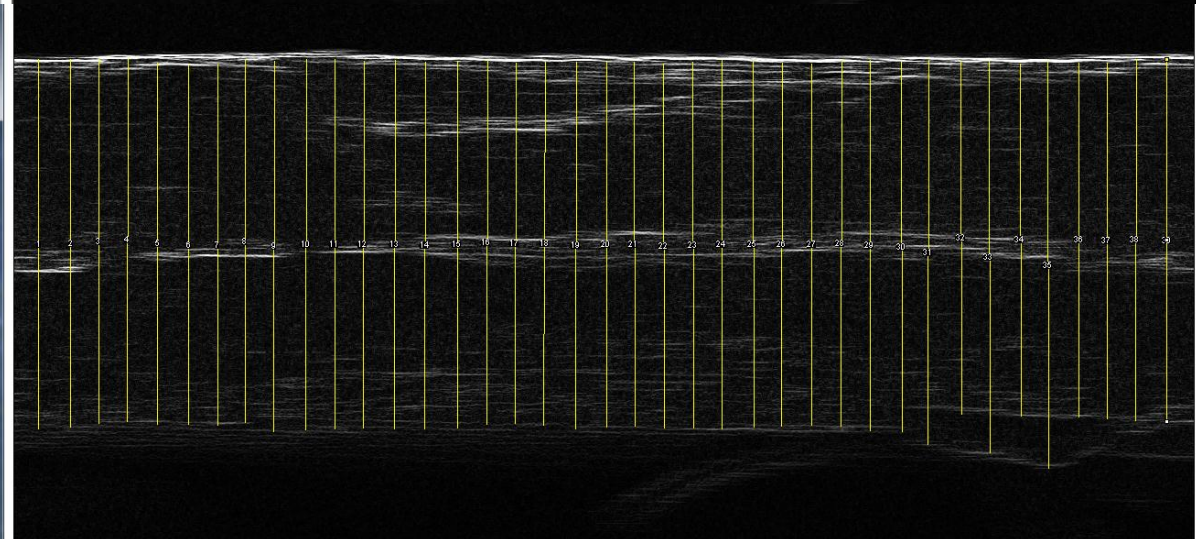
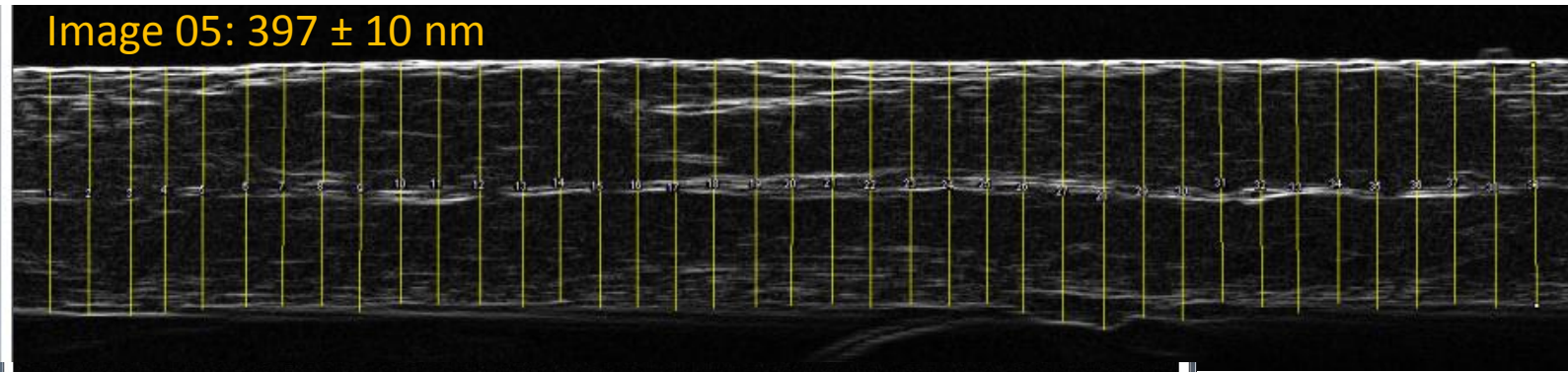
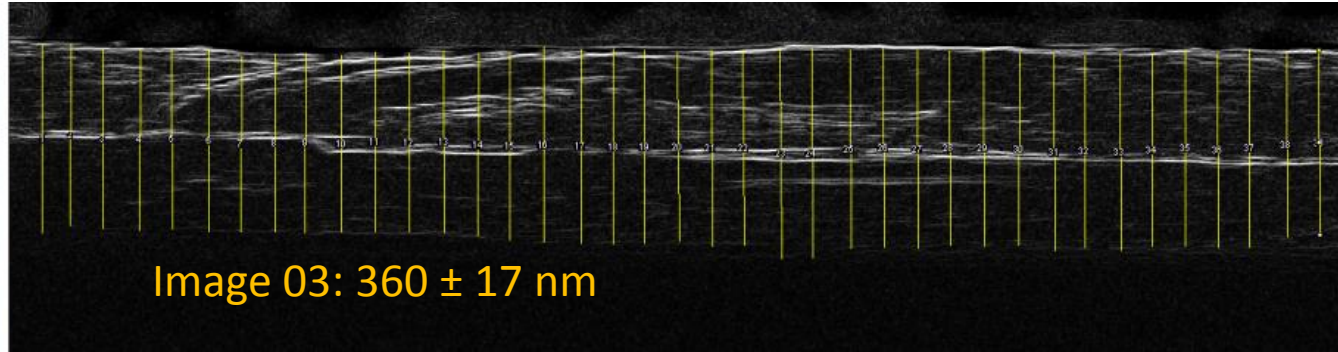
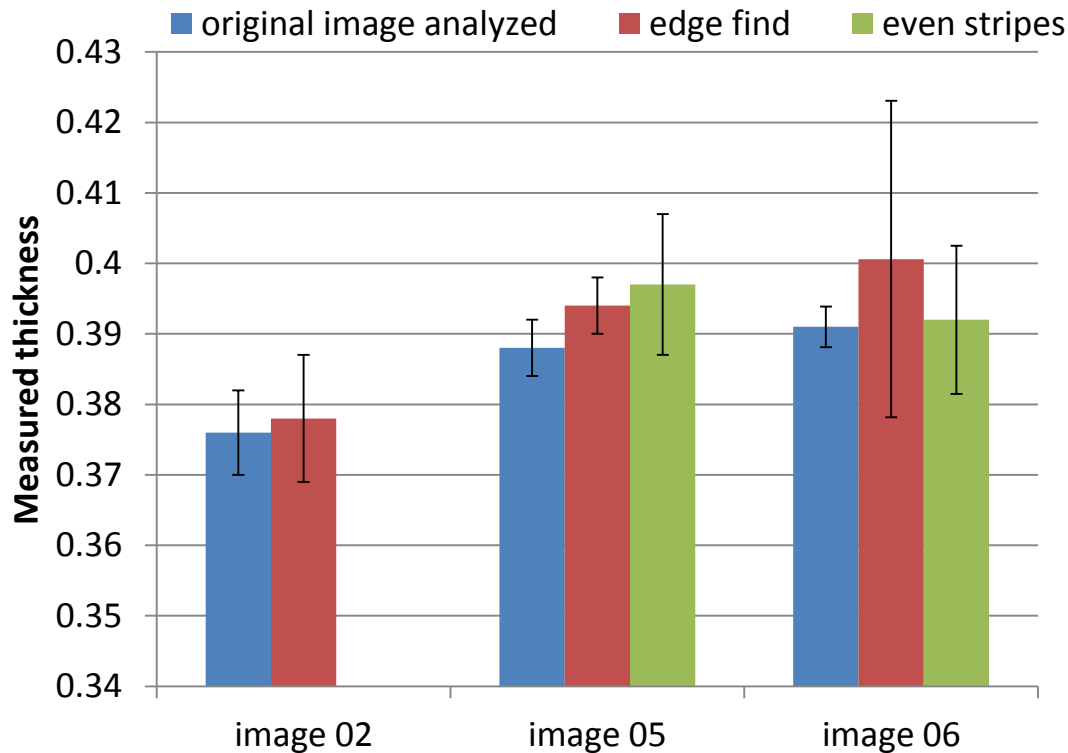


Image 06: 392 ± 10.5 nm

Conclusions: 5613D

Effect of measurement style



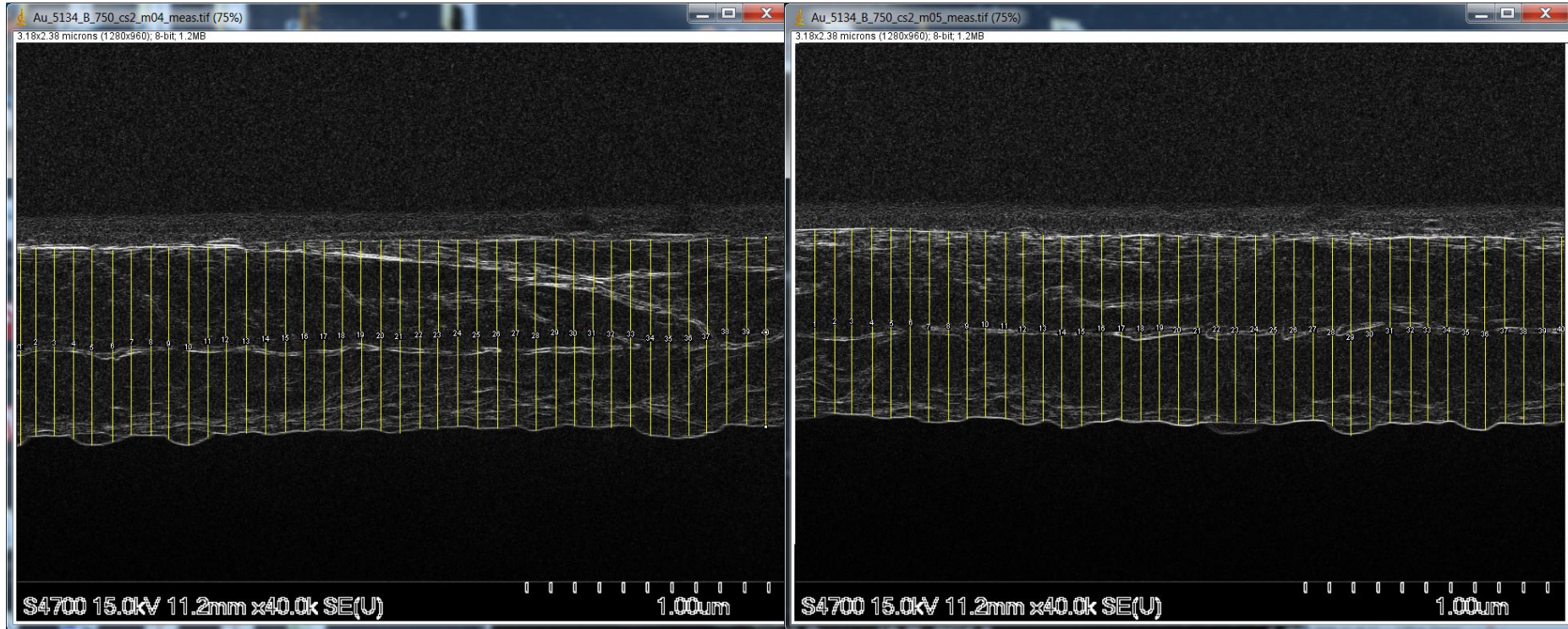
Edge find image,
Weighted mean
0.392 microns \pm 0.0036

Original image,
Weighted mean
0.388 microns \pm 0.0022

Even stripes image,
Weighted mean
0.389 microns \pm 0.0066

Thickness is robust to within error bars for any of the methods

Foil 5134

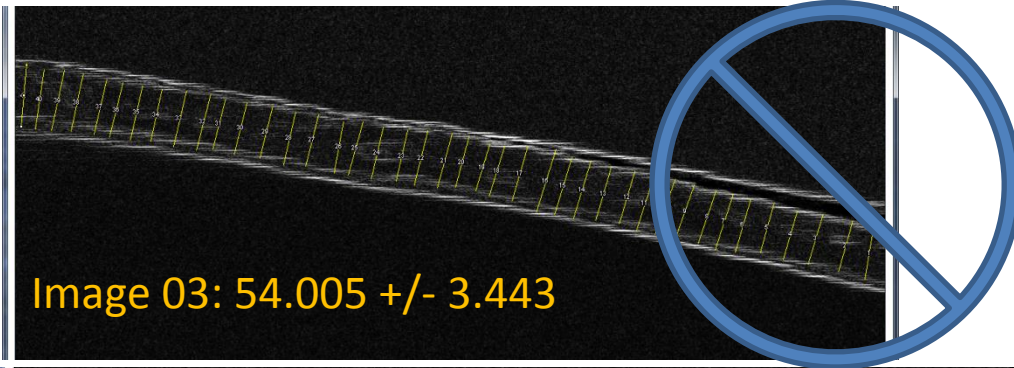


$782 \pm 16 \text{ nm}$

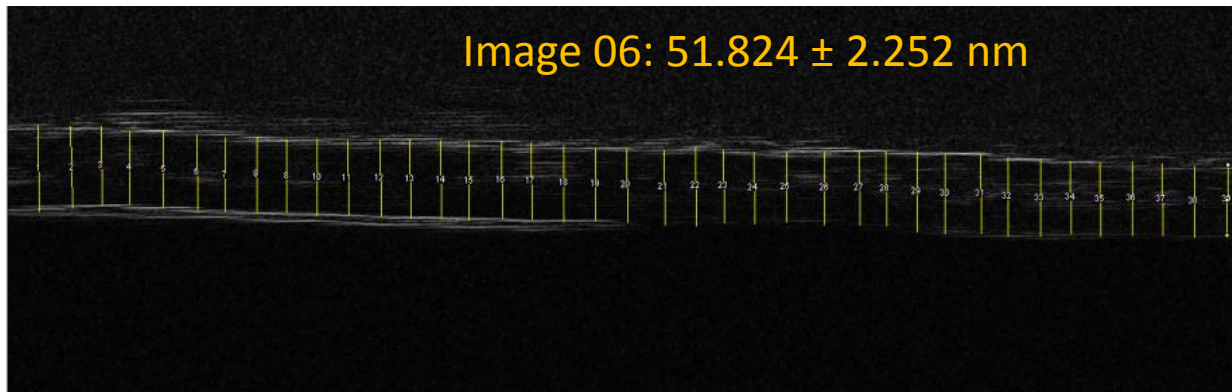
$772 \pm 13 \text{ nm}$

Average: $776 \text{ nm} \pm 10.1$

Foil 6809



51.539 ± 2.766



Ladder position	Foil number	Quoted thickness (nm)	Measured thickness (nm)
13	6845	50 ± 5	51.539 ± 2.766
1	7029	225 ± 22.5	
8	5613	350 ± 35	389 ± 6.6
5	5275	500 ± 50	
2	7028	625 ± 62.5	
4	5134	750 ± 75	$776 \text{ nm} \pm 10.1$
3	3057	870 ± 87	
15	5385	1000 ± 100	

Asymmetry vs. Foil thickness

